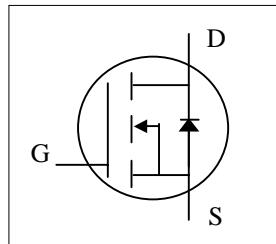
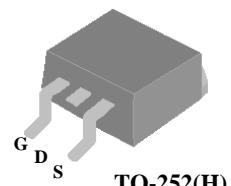




- ▼ Fast Switching Characteristic
- ▼ Simple Drive Requirement
- ▼ RoHS Compliant & Halogen-Free



BV_{DSS}	650V
$R_{DS(ON)}$	0.65Ω
I_D	7A



Description

AP07S60 series are from Advanced Power innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The TO-252 package is widely preferred for commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters.

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	650	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_c = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	7	A
$I_D @ T_c = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	4.3	A
I_{DM}	Pulsed Drain Current ¹	16	A
$P_D @ T_c = 25^\circ C$	Total Power Dissipation	83.3	W
$P_D @ T_A = 25^\circ C$	Total Power Dissipation ³	2	W
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Units
R_{thj-c}	Maximum Thermal Resistance, Junction-case	1.5	°C/W
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient (PCB mount) ³	62.5	°C/W



Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\mu\text{A}$	650	-	-	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=3.5\text{A}$	-	-	0.65	Ω
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$	2	-	4	V
g_{fs}	Forward Transconductance	$\text{V}_{\text{DS}}=10\text{V}, \text{I}_D=3.5\text{A}$	-	6.6	-	S
I_{DSS}	Drain-Source Leakage Current	$\text{V}_{\text{DS}}=480\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	100	μA
I_{GSS}	Gate-Source Leakage	$\text{V}_{\text{GS}}=\pm 20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Q_{g}	Total Gate Charge	$\text{I}_D=3.5\text{A}$	-	26	41.6	nC
Q_{gs}	Gate-Source Charge	$\text{V}_{\text{DS}}=480\text{V}$	-	3	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$\text{V}_{\text{GS}}=10\text{V}$	-	12.5	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time	$\text{V}_{\text{DD}}=300\text{V}$	-	9	-	ns
t_r	Rise Time	$\text{I}_D=3.5\text{A}$	-	9	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$\text{R}_G=3.3\Omega$	-	32	-	ns
t_f	Fall Time	$\text{V}_{\text{GS}}=10\text{V}$	-	10	-	ns
C_{iss}	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}$	-	680	1088	pF
C_{oss}	Output Capacitance	$\text{V}_{\text{DS}}=25\text{V}$	-	430	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	10	-	pF
R_{g}	Gate Resistance	f=1.0MHz	-	4.5	9	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$\text{I}_S=3.5\text{A}, \text{V}_{\text{GS}}=0\text{V}$	-	0.8	-	V
t_{rr}	Reverse Recovery Time	$\text{I}_S=3.5\text{A}, \text{V}_{\text{GS}}=0\text{V}$	-	160	-	ns
Q_{rr}	Reverse Recovery Charge	$d\text{I}/dt=100\text{A}/\mu\text{s}$	-	1.25	-	μC

Notes:

- 1.Pulse width limited by max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in² copper pad of FR4 board

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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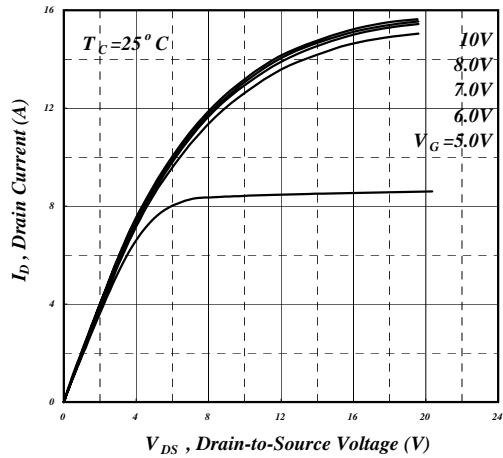


Fig 1. Typical Output Characteristics

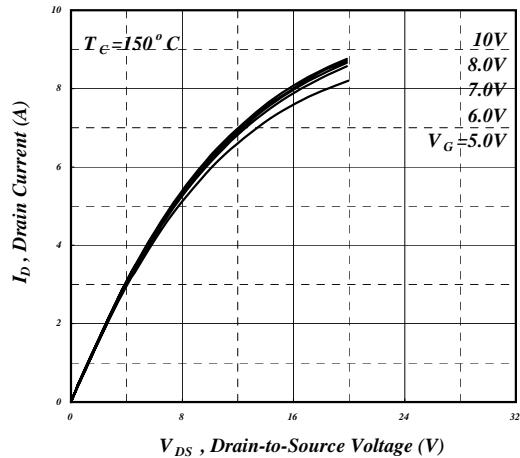


Fig 2. Typical Output Characteristics

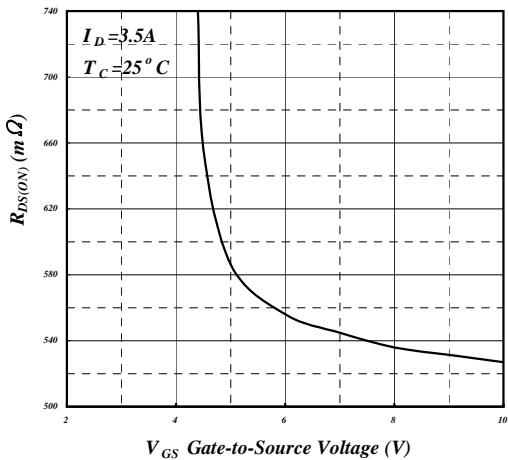


Fig 3. On-Resistance v.s. Gate Voltage

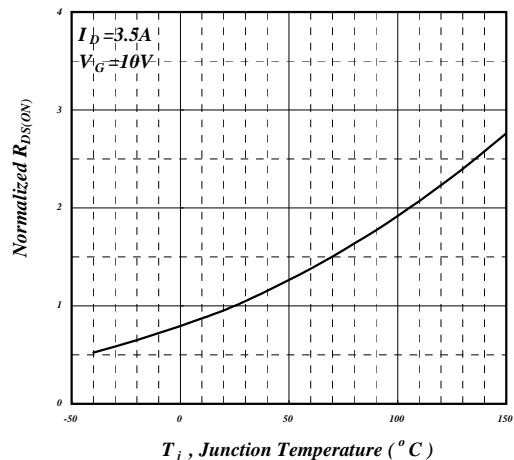


Fig 4. Normalized On-Resistance v.s. Junction Temperature

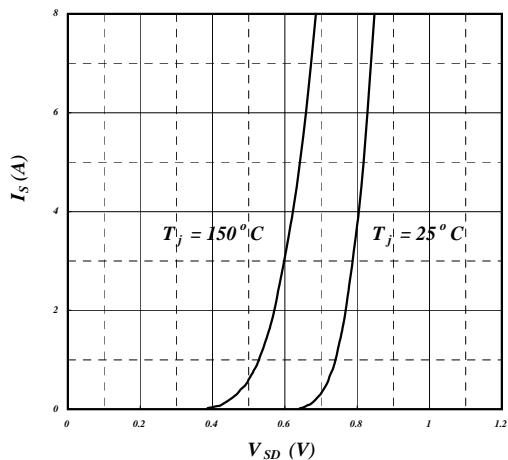


Fig 5. Forward Characteristic of Reverse Diode

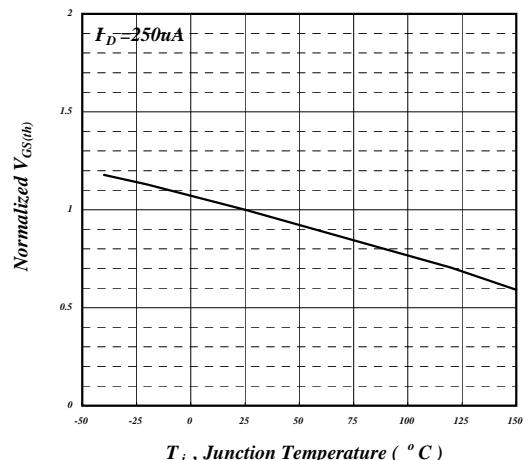


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

